#### **VLSI Design Verification and Testing**

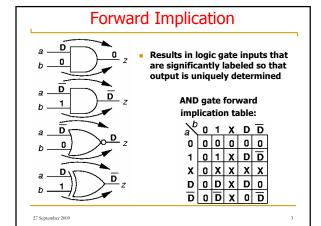
#### **Combinational ATPG**

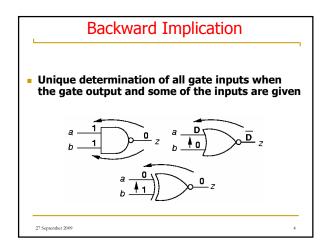
Mohammad Tehranipoor Electrical and Computer Engineering University of Connecticut

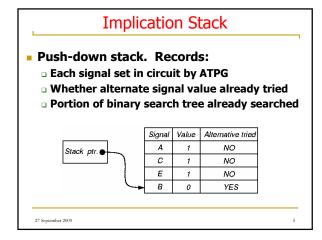
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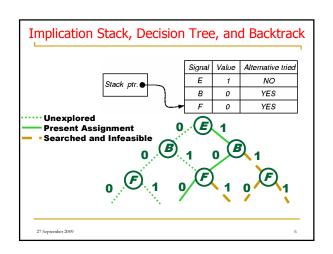
#### Overview: Major ATPG Algorithms

- Definitions
- D-Algorithm (Roth) -- 1966
  - D-cubes
  - Bridging faults
  - Logic gate function change faults
- PODEM (Goel) -- 1981
  - X-Path-Check
  - Backtracing
- Summary









#### Objectives and Backtracing in ATPG

- Objective desired signal value goal for ATPG
  - Guides it away from infeasible/hard solutions
  - Uses heuristics
    - E.g. which fault site to choose first?
- Backtrace Determines which primary input and value to set to achieve objective
  - Use heuristics such as nearest PI
- Forward trace Determines gate through which the fault effect should be sensitized
  - Use heuristics selecting output that is closest to the present fault effect

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#### **Branch-and-Bound Search**

- Efficiently searches binary search tree
- Branching At each tree level, selects which input variable to set to what value
- Bounding Avoids exploring large tree portions by artificially restricting search decision choices
  - Complete exploration is impractical
  - Uses heuristics
- Example:
  - For a circuit with inputs A, B, C, D and E: AB.... does not achieve objective.

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D-Algorithm - Roth (1966)

- Fundamental concepts invented:
  - First complete ATPG algorithm
  - D-Cube
  - D-Calculus
  - □ Implications forward and backward
  - Implication stack
  - Backtrack
  - □ Test Search Space

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Singular Cover - Example  Minimal set of logic signal assignments to represent a function  Show prime implicants and prime implicates of Karnaugh map (with explicitly showing the outputs too)  A  B  C  B  C  B  C  B  C  B  C  C  B  C  C										
		Gate Inputs Output Gate Inputs Output								
 								output		
	Gate AND	Α	В	d	Gate NOR		e	F		
				<i>d</i>	NOR 1			<i>F</i>		
		Α	В	d			e	F		

#### D-Cube - Example

- Collapsed truth table entry to characterize logic
- Use Roth's 5-valued algebra
- Can change all D's to D's and D's to D's (do both)
- AND gate:

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	A	B	d	
Rows 3 & 1	D	1	D	
Reverse inputs	1	D	D	AND Gate
AND two cubes	D	D	D	Propagation D-Cubes
Interchange D and D	D	D	D	D-Cubes
	1	D	D	
	D	1	D	

### D-Cube Operation of D-Intersection

- ψ undefined (same as φ)
- $\mu$  or  $\lambda$  requires inversion of D and  $\overline{D}$
- *D-intersection*:  $0 \cap 0 = 0 \cap X = X \cap 0 = 0$  $1 \cap 1 = 1 \cap X = X \cap 1 = 1$

 $X \cap X = X$ 

D-containment —
 Cube a contains
 Cube b if b is a
 subset of a

$\cap$	0	1	Х	D	D
0	0	φ 1	0	Ψ	Ψ
X	ŏ	1	X	Ď	D
ㅁ	Ψ	Ψ	D D	μ λ	λ μ

#### Primitive D-Cube of Failure (PDF)

- Models circuit faults:
  - □ Stuck-at-0
  - □ Stuck-at-1
  - Other faults, such as Bridging fault (short circuit)
  - Arbitrary change in logic function
- AND Output sa0: "1 1 D"
- AND Output sa1: "0 X \overline{D}"
  "X 0 \overline{D}"
- Wire sa0:
- Propagation D-cube models conditions under which fault effect propagates through gate

"D"

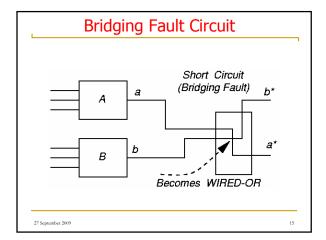
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#### **Implication Procedure**

- 1. Model fault with appropriate *primitive D-cube of failure* (PDF)
- Select propagation D-cubes to propagate fault effect to a circuit output (D-drive procedure)
- Select singular cover cubes to justify internal circuit signals (Consistency procedure)
- Put signal assignments in test cube
- Regrettably, cubes are selected very arbitrarily by D-ALG

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## Construction of Primitive D-Cubes of Failure

- 1. Make cube set  $\alpha 1$  when good machine output is 1 and set  $\alpha 0$  when good machine output is 0
- 2. Make cube set  $\beta 1$  when failing machine output is 1 and  $\beta 0$  when it is 0
- 3. Change  $\alpha 1$  outputs to 0 and D-intersect each cube with every  $\beta 0$ . If intersection works, change output of cube to D
- 4. Change  $\alpha 0$  outputs to 1 and D-intersect each cube with every  $\beta 1$ . If intersection works, change output of cube to  $\overline{D}$

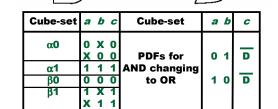
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#### Bridging Fault D-Cubes of Failure

Cube-set	а	b	a*	b*	Cube-set	a b a*	<b>b</b> *
α0	0	Х	0	Х			
	X	0	X	0			
α1	1	Х	1	Х	PDFs for	101	D
	X	1	X	1	PDFs for Bridging fault	0 1 D	1
β0	0	0	0	0			
β1	X	1	1	1			
•	1	X	1	1			

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## Gate Function Change D-Cube of Failure



#### **Propagation D-Cube**

- Collapsed truth table entry to characterize logic
- Use Roth's 5-valued algebra
- $\blacksquare$  AND gate: use the rules given earlier using  $\alpha$  and β but in this case work with good circuit only

1 D Write all primitive **Cubes of AND gate** D D and then create D D D propagation cubes D

#### D-Algorithm - Top Level

- 1. Number all circuit lines in increasing level order from PIs to POs;
- Select a primitive D-cube of the fault to be the test cube;
  - ☐ Put logic outputs with inputs labeled as D (D) onto the *D-frontier*;
- D-drive();
- Consistency ();
- return ();

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#### D-Algorithm -- D-drive

while (untried fault effects on D-frontier)

select next untried D-frontier gate for propagation; while (untried fault effect fanouts exist)

select next untried fault effect fanout;

generate next untried propagation D-cube;

- D-intersect selected cube with test cube:
- if (intersection fails or is undefined) continue;
- if (all propagation D-cubes tried & failed) break:

if (intersection succeeded)

add propagation D-cube to test cube -- recreate D-frontier; Find all forward & backward implications of assignment; save *D-frontier*, algorithm state, test cube, fanouts, fault;

else if (intersection fails & D and  $\overline{D}$  in test cube) Backtrack (); else if (intersection fails) break;

if (all fault effects unpropagatable) Backtrack ();

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#### D-Algorithm -- Consistency

g =coordinates of test cube with 1's & 0's;

if (g is only PIs) fault testable & stop;

for (each unjustified signal in g)

Select highest # unjustified signal z in g, not a PI;

if (inputs to gate z are both D and D) break;

while (untried singular covers of gate z) select next untried singular cover;

if (no more singular covers)

If (no more stack choices) fault untestable & stop; else if (untried alternatives in *Consistency*)

pop implication stack -- try alternate assignment; else

Backtrack(); D-drive ();

If (singular cover D-intersects with z) delete z from g, add inputs to singular cover to g, find all forward and backward implications of new assignment, and break;

If (intersection fails) mark singular cover as failed;

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#### **Backtrack**

if (PO exists with fault effect) Consistency (); else pop prior implication stack setting to try alternate

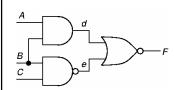
if (no untried choices in implication stack)

ault untestable & stop;

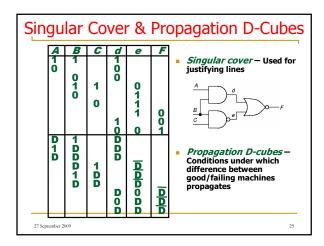
else return;

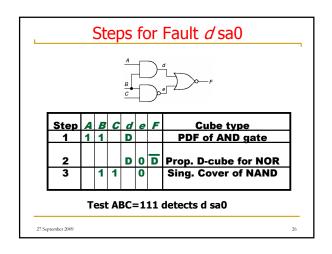
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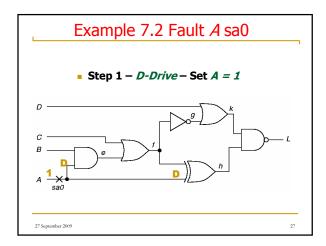
#### Circuit Example 7.1 and Truth Table

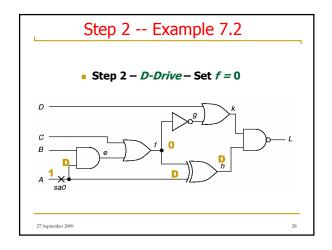


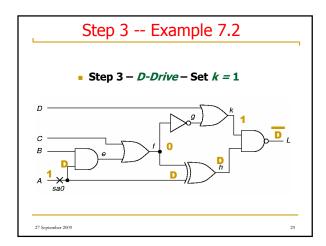
Li	nput	Output	
a	b	C	F
0	0	0	0
0	0	1	0
0	1	0	0
0	1	1	1
1	0	0	0
1	0	1	0
1	1	0	0
1 1	1	1	0

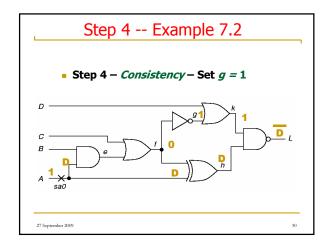


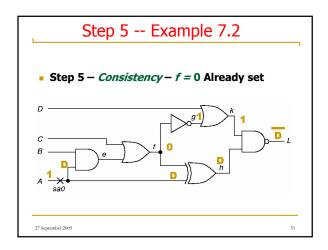


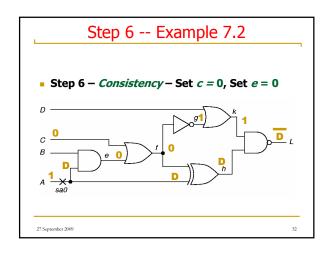


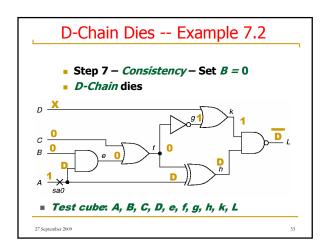


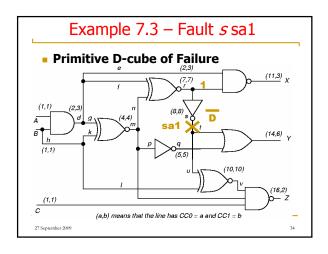


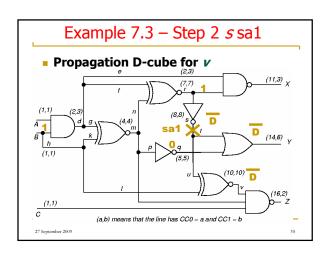


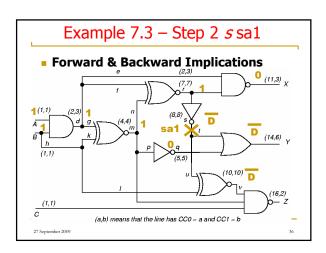


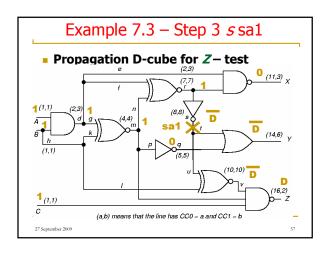


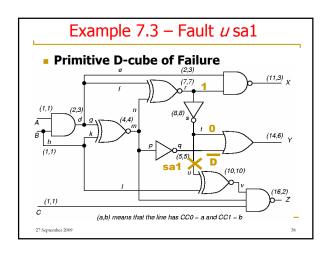


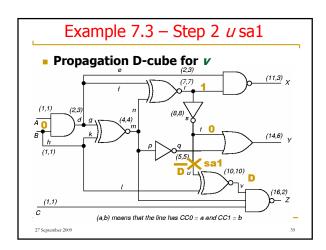


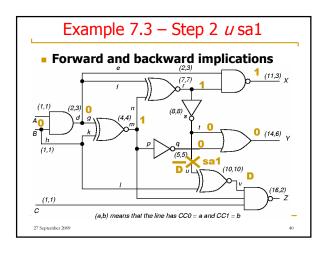


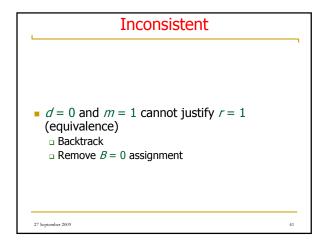


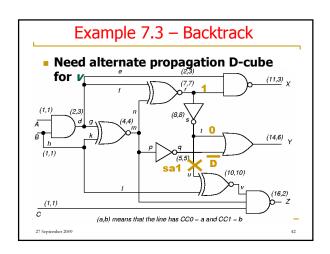


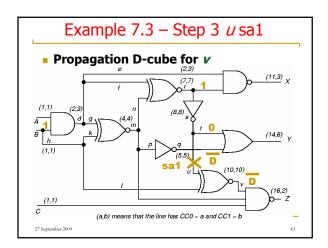


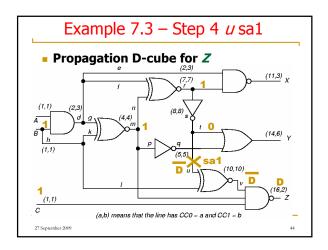


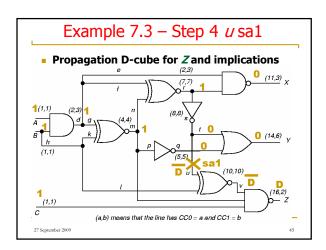


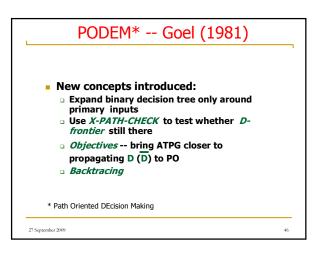






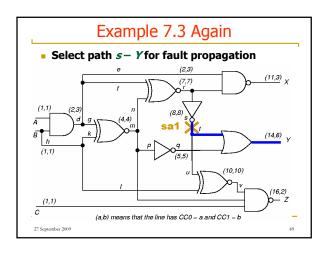


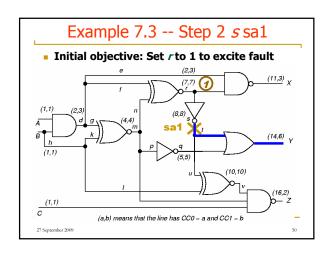


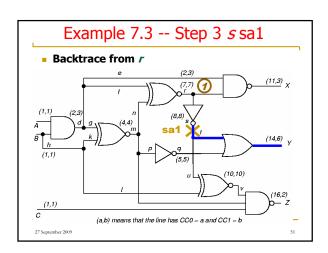


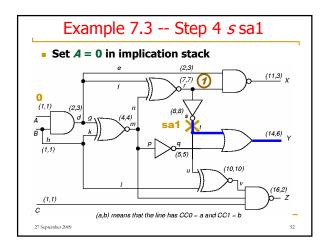
# Motivation IBM introduced semiconductor DRAM memory into its mainframes – late 1970's Memory had error correction and translation circuits – improved reliability D-ALG unable to test these circuits Search too undirected Large XOR-gate trees Must set all external inputs to define output Needed a better ATPG tool

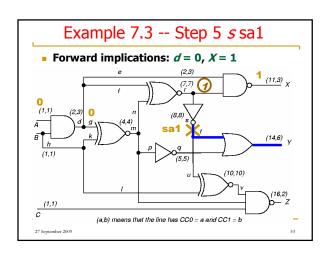
## Assign binary value to unassigned PI Determine implications of all PIs Test Generated? If so, done. Test possible with more assigned PIs? If maybe, go to Step 1 Is there untried combination of values on assigned PIs? If not, exit: untestable fault Set untried combination of values on assigned PIs using objectives and backtrace. Then, go to Step 2

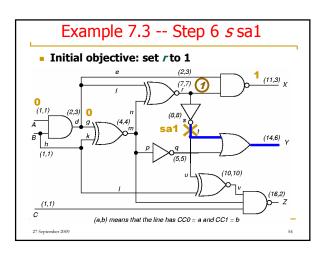


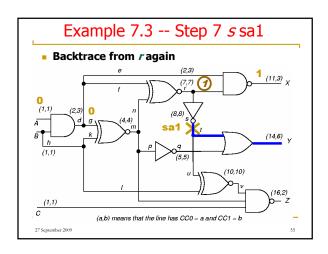


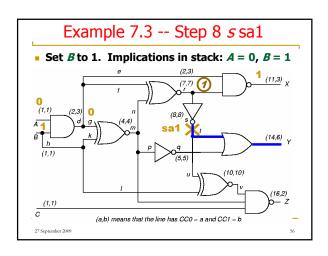


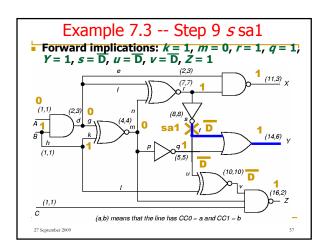


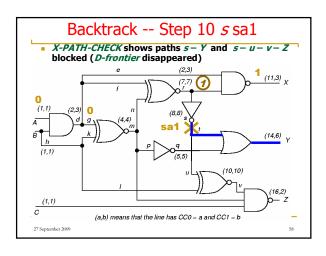


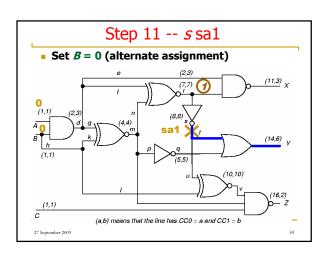


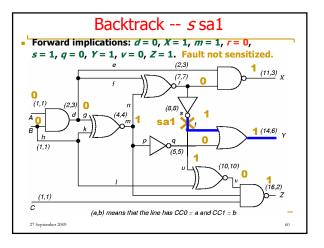


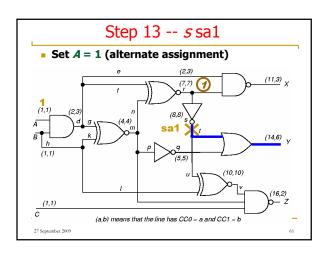


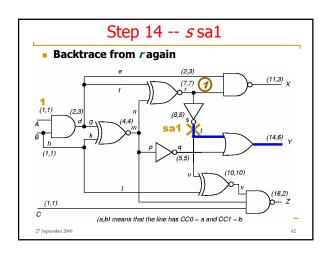


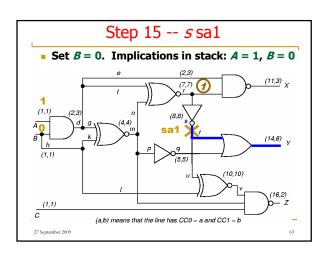


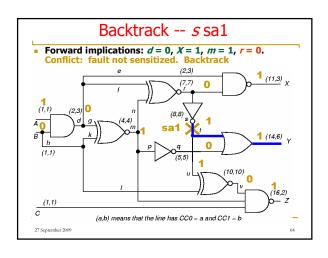


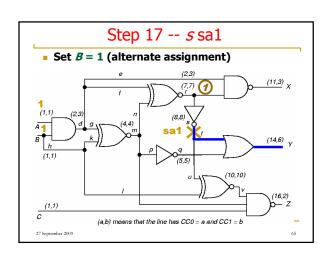


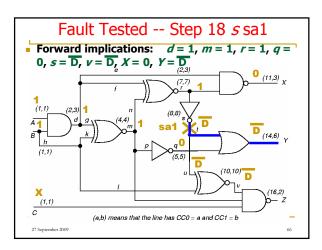












#### Backtrace (s, v<sub>s</sub>) Pseudo-Code

```
v = v;
while (s is a gate output)
if (s is NAND or INVERTER or NOR) v = v;
if (objective requires setting all inputs)
    select unassigned input a of s with hardest
    controllability to value v;
else
    select unassigned input a of s with easiest
    controllability to value v;
s = a;
return (s, v) /* Gate and value to be assigned
*/;
```

#### Objective Selection Code

```
if (gate g is unassigned) return (g, \overline{v}); select a gate P from the D-frontier; select an unassigned input / of P, if (gate g has controlling value)

c = controlling input value of g; else if (0 value easier to get at input of XOR/EQUIV gate)

c = 1; else c = 0; return (/, \overline{c});
```

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#### **PODEM** Algorithm

```
while (no fault effect at POs)
if (xpathcheck (D-frontier)

(l, v_l) = Objective (fault, v_{fault});
(pi, v_{pi}) = Backtrace (l, v_l);
Imply (pi, v_{pi});
if (PODEM (fault, v_{fault}) == SUCCESS) return (SUCCESS);
(pi, v_{pi}) = Backtrack ();
Imply (pi, v_{pi});
if (PODEM (fault, v_{fault}) == SUCCESS) return (SUCCESS);
Imply (pi, v_{pi});
return (FAILURE);
else if (implication stack exhausted)
return (FAILURE);
else Backtrack ();
return (SUCCESS);
```

#### **Summary**

- D-ALG First complete ATPG algorithm
  - □ *D-Cube*
  - D-Calculus
  - $\ {\scriptstyle \square}$   ${\color{blue} Implications}$  – forward and backward
  - □ Implication stack
  - Backup
- PODEM
  - $\ {\scriptstyle \square}$  Expand decision tree only around PIs
- □ Use X-PATH-CHECK to see if D-frontier exists
- Objectives -- bring ATPG closer to getting
   D (D) to PO
- Backtracing